

TEMIC

Siliconix

SUP/SUB70N06-14

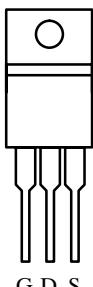
N-Channel Enhancement-Mode Transistors

175°C Maximum Junction Temperature

Product Summary

$V_{(BR)DSS}$ (V)	$r_{DS(on)}$ (Ω)	I_D (A)
60	0.014	70 ^a

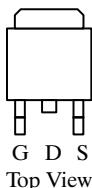
TO-220AB



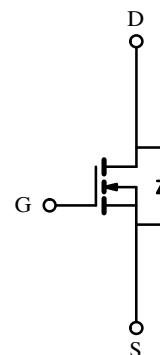
Top View

SUP70N06-14

TO-263



SUB70N06-14



N-Channel MOSFET

Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ($T_J = 175^\circ\text{C}$)	I_D	70 ^a	A
$T_C = 100^\circ\text{C}$		49	
Pulsed Drain Current	I_{DM}	160	
Avalanche Current	I_{AR}	70	
Repetitive Avalanche Energy ^b	E_{AR}	180	mJ
Power Dissipation	P_D	142 ^c	W
$T_A = 25^\circ\text{C}$ (TO-220AB and TO-263)		3.7	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 175	°C

Thermal Resistance Ratings

Parameter	Symbol	Limit	Unit
Junction-to-Ambient	R_{thJA}	40	°C/W
Free Air (TO-220AB)		62.5	
Junction-to-Case	R_{thJC}	1.05	

Notes:

- a. Package limited.
- b. Duty cycle $\leq 1\%$.
- c. See SOA curve for voltage derating.
- d. When mounted on 1" square PCB (FR-4 material).

Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_{DS} = 1 \text{ mA}$	2.0	3.0	4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	μA
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			150	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	70			A
Drain-Source On-State Resistance ^b	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$			0.014	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$			0.023	Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$			0.028	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$	25	50		S
Dynamic^a						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$			2400	
Output Capacitance	C_{oss}				490	
Reversen Transfer Capacitance	C_{rss}				130	pF
Total Gate Charge ^c	Q_g	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$			45	
Gate-Source Charge ^c	Q_{gs}				12	
Gate-Drain Charge ^c	Q_{gd}				16	nC
Turn-On Delay Time ^c	$t_{d(\text{on})}$	$V_{DD} = 30 \text{ V}, R_L = 0.47 \Omega$ $I_D \approx 60 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 2.5 \Omega$			13	
Rise Time ^c	t_r				11	ns
Turn-Off Delay Time ^c	$t_{d(\text{off})}$				30	
Fall Time ^c	t_f				11	25
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)^a						
Continuous Current	I_s				70	
Pulsed Current	I_{SM}				160	A
Forward Voltage ^b	V_{SD}	$I_F = 70 \text{ A}, V_{GS} = 0 \text{ V}$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 60 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}$			47	
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$				3.5	
Reverse Recovery Charge	Q_{rr}				0.08	μC

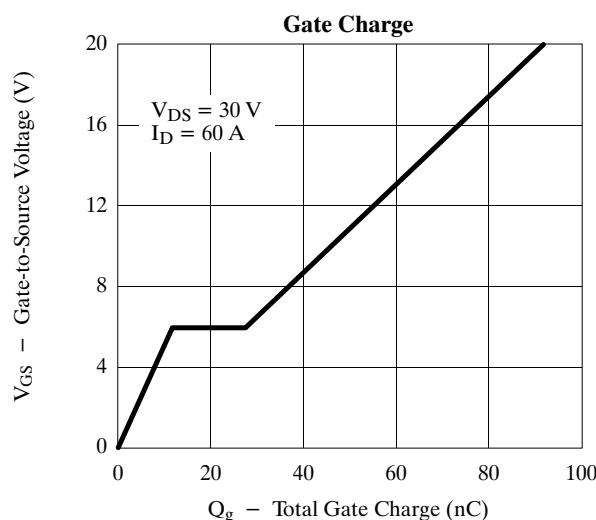
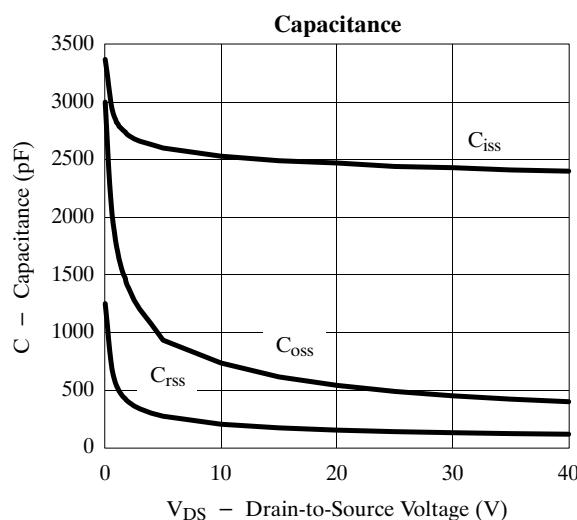
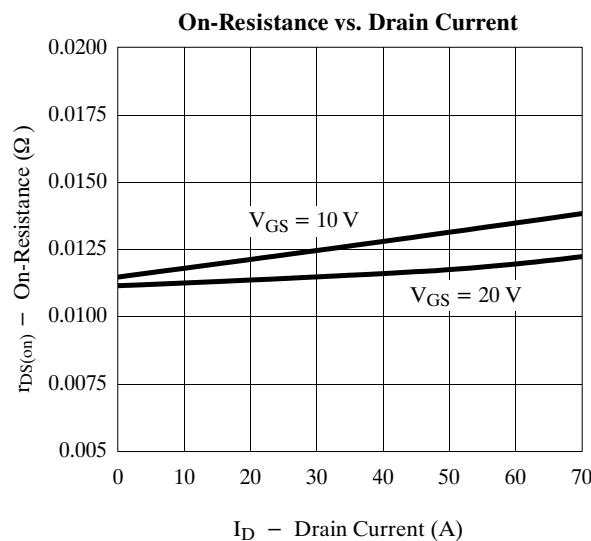
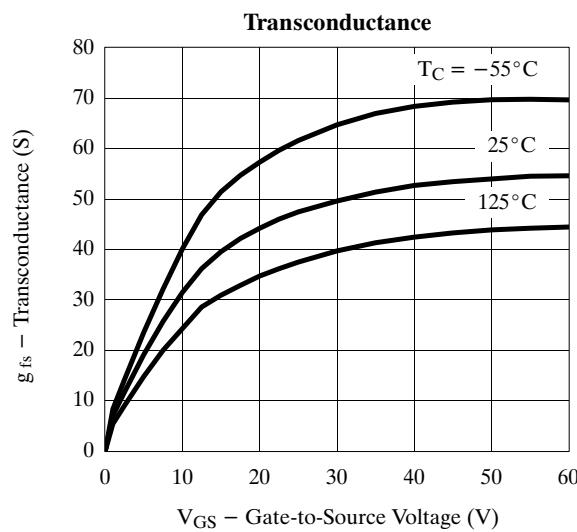
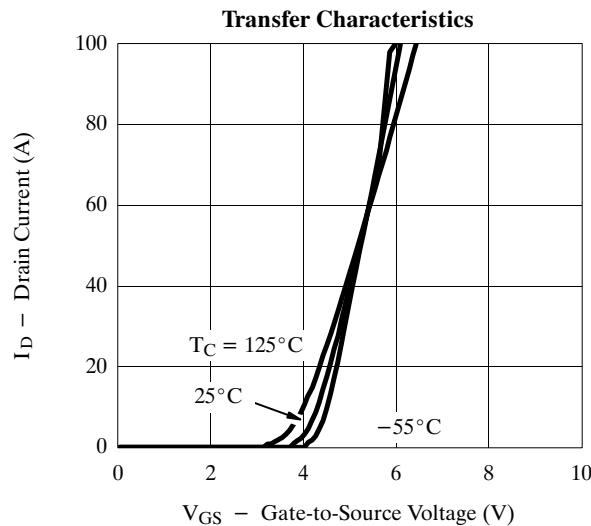
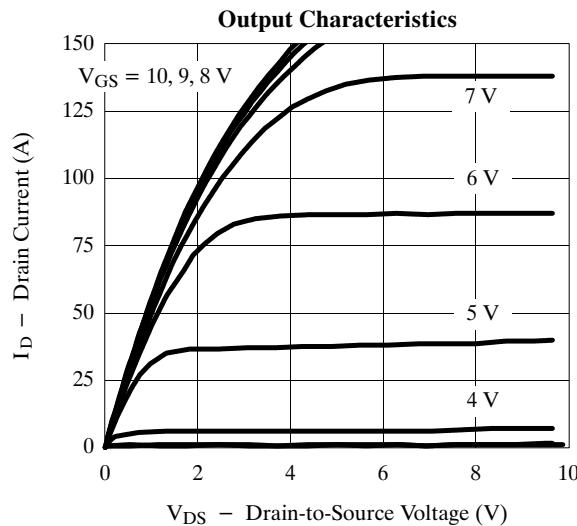
Notes:

a. Guaranteed by design, not subject to production testing.

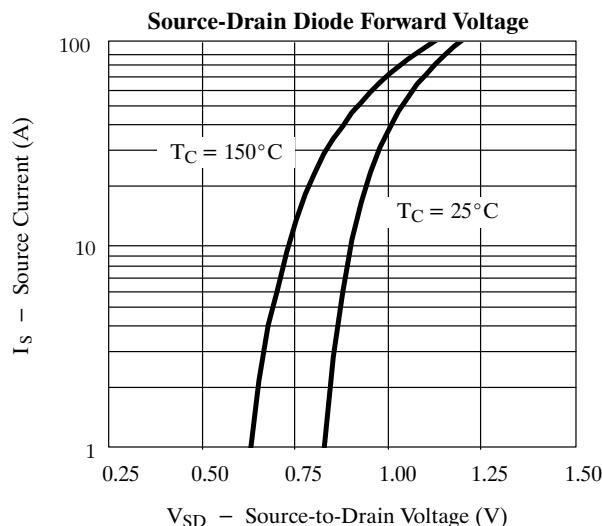
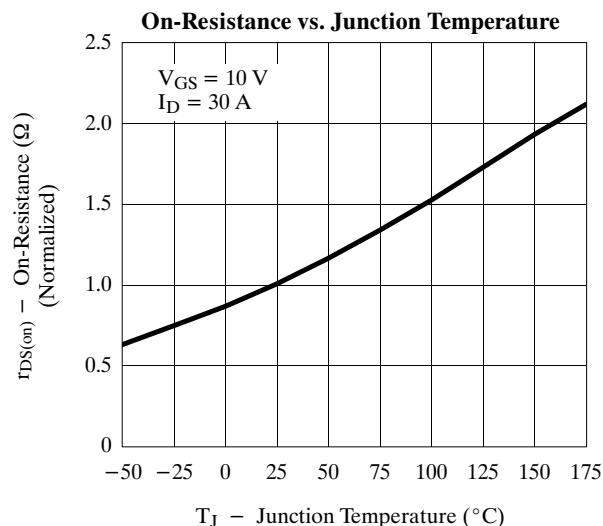
b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

c. Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



Typical Characteristics (25°C Unless Otherwise Noted)



Thermal Ratings

